



Vibration Testing Underway



Noise and vibrations can cause problems with data obtained by the AFM. One strategy to determine the cause of problem scans is to acquire vibration measurements during a scan and compare with problems shown on the scan. Pictured here with Olga is Kurt Davis from JLab's Test Lab Group. Kurt is shown setting up his equipment to test the AFM for damaging mechanical vibrations.

SEM-S570 at the Integrated Science Center



The Hitachi Scanning Electron Microscope is now successfully installed and up and running in the ISC. Shown here is Melissa Pocock, a WM Graduate student using the SEM for her work.

Amy is pictured here with Carla Jones, RN. Carla came to visit the lab and Amy.



Lab tour & Demonstration



WM-ARC hosted the ASM Materials Information Society three-day International Failure Analysis course at the ARC on May 19-21, 2009. During the course we also hosted a lab tour with demonstrations for the group of 20 participants.

Lab Welcomes Newest & Youngest Member of the Family



Mingyao Zhu and Haijian Chen – Two research scientists, who work in our lab, welcomed Alyssa into their life on February 2nd, 2009. Pictured above are Mingyao and Alyssa.